

Atomic Level Side Faceting in Hf doped Alumina: A Primary Study

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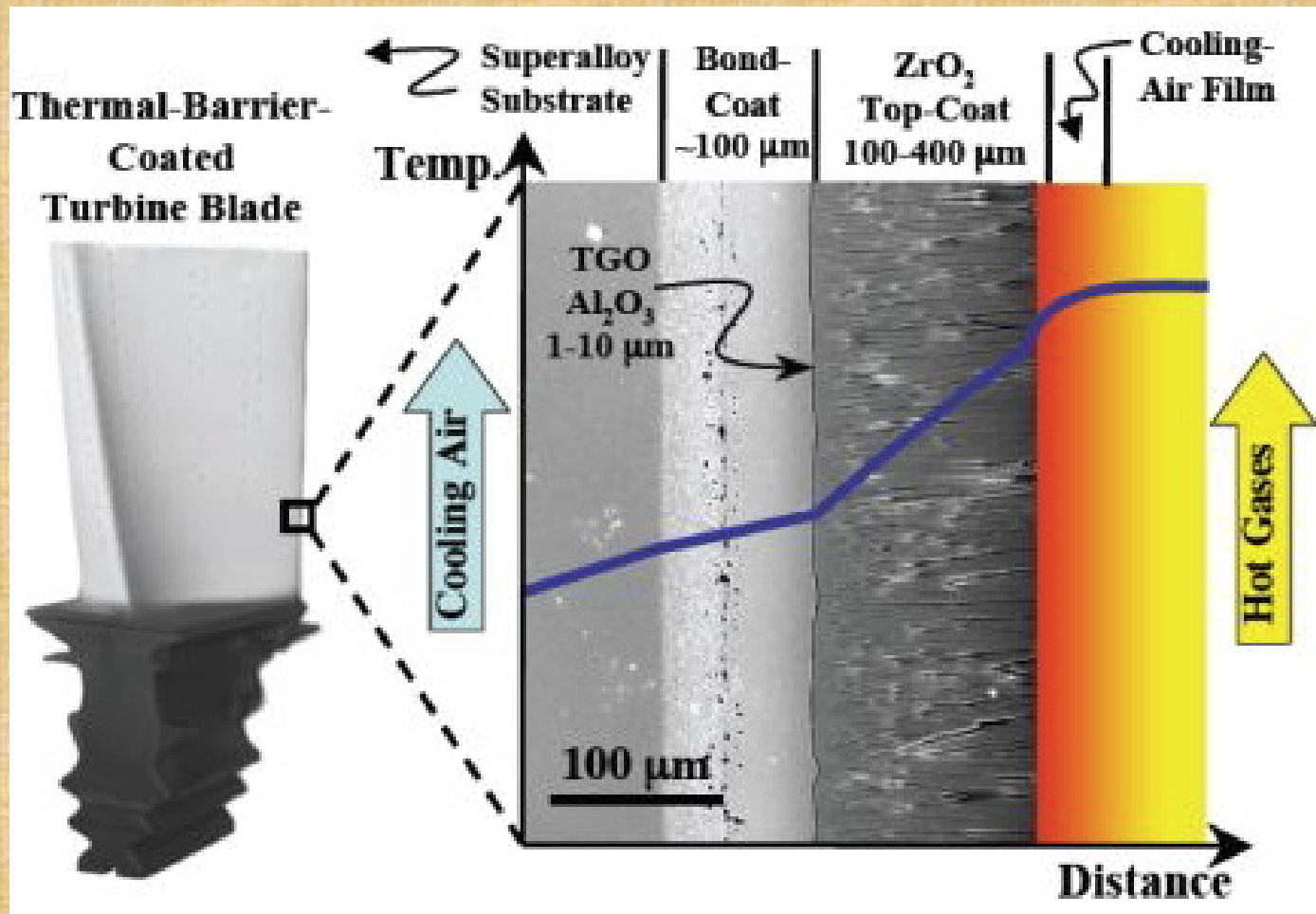
H. M. Chan; J. M. Rickman; M. P. Harmer

Outline

- Introduction
- General observation of Hf-doped GB
- Atomic scale side faceting in the GB
- Conclusions

Turbine blades and TBCs

(MCrAlY)



Thermal barrier coatings (TBCs) for gas-turbine engine applications

With RE additions...

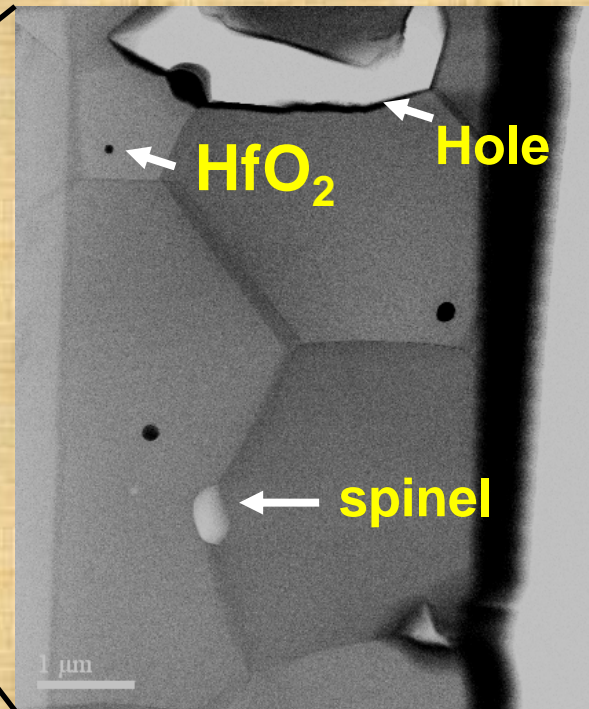
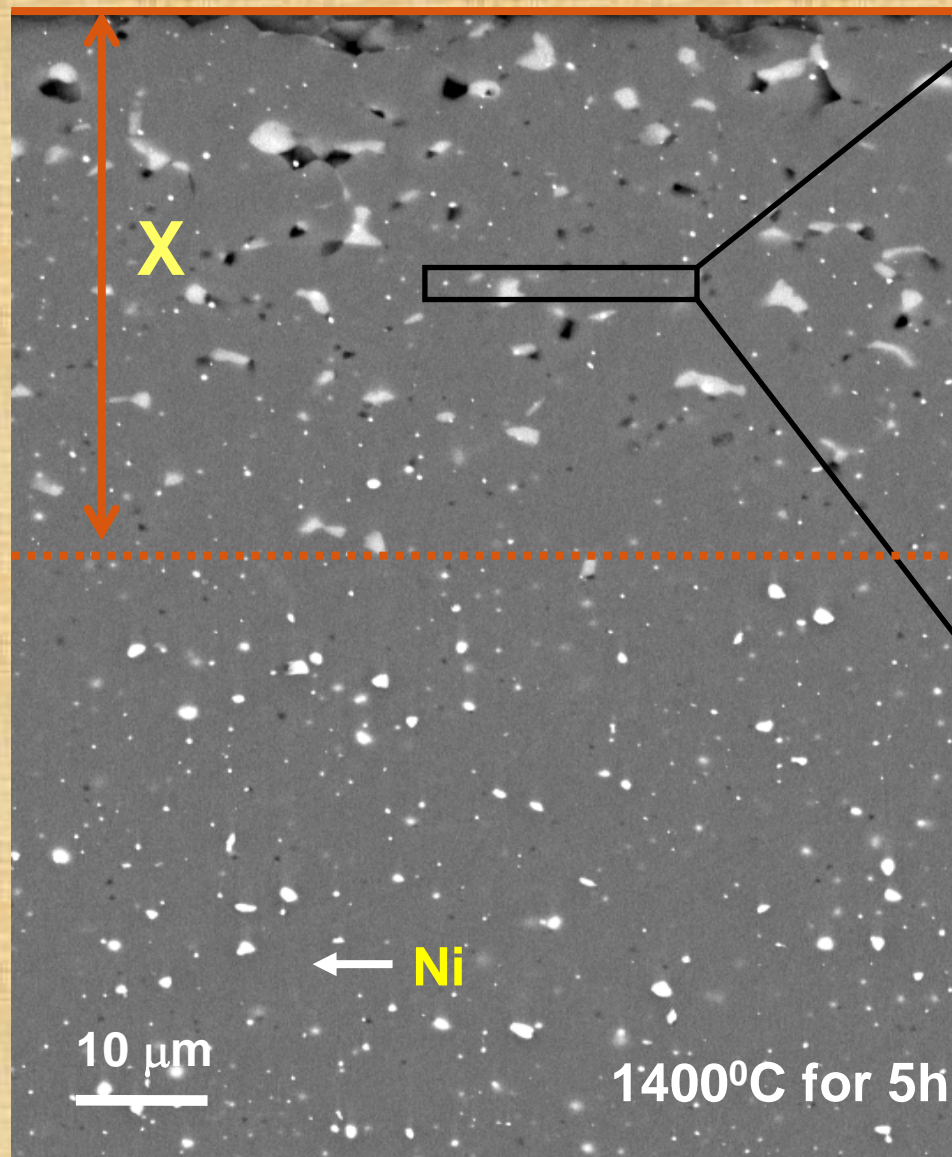
Reactive element additives (e.g. Y,Hf) are beneficial to oxidation behavior of alumina formers.

- **Improving adhesion of scale**
- **Slowing transport kinetics**
- **Modifying microstructure of scale**

Outline

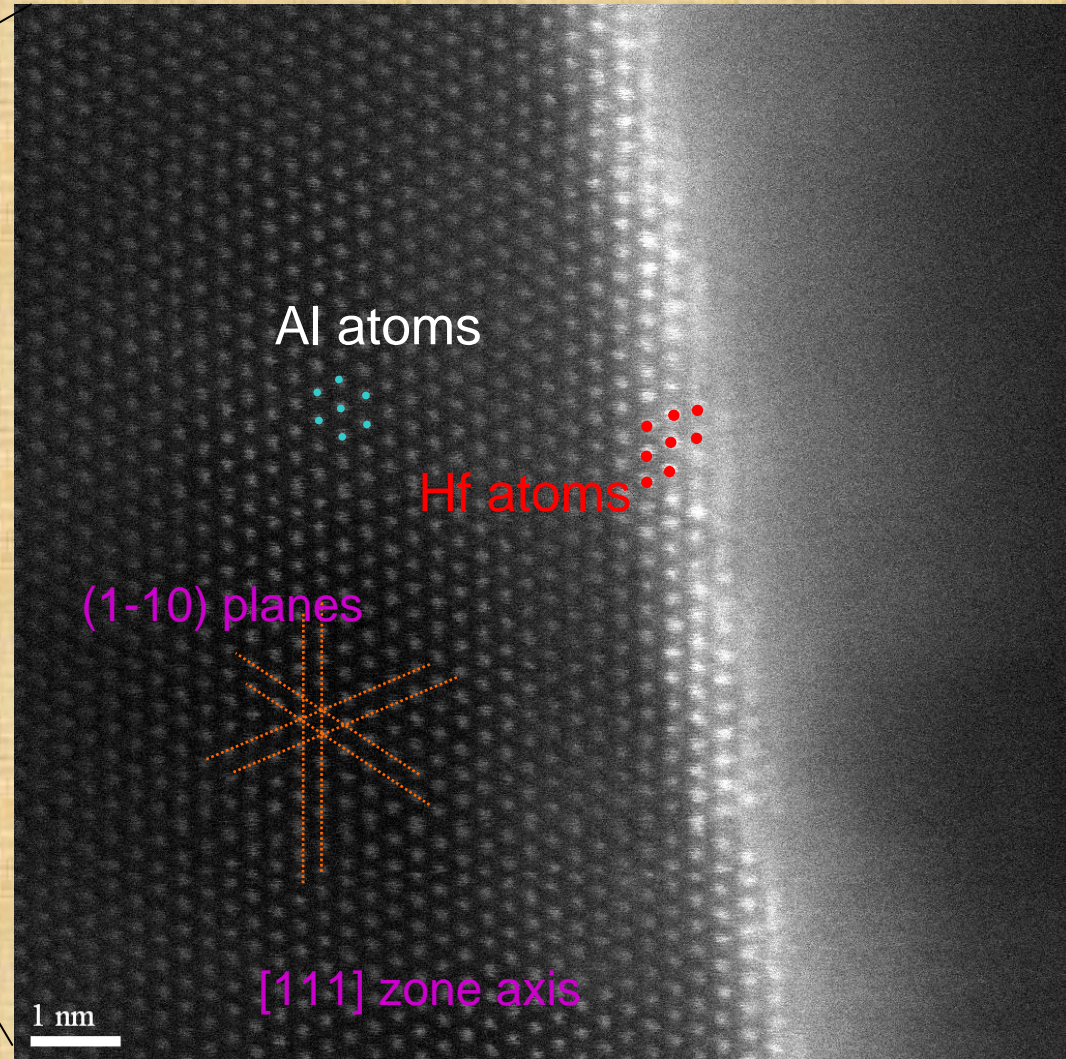
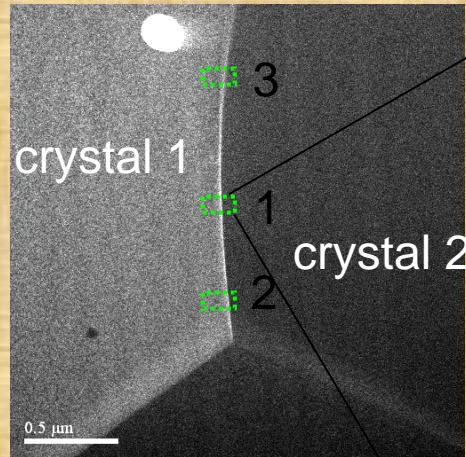
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FIB Sample – 500ppm Hf doped



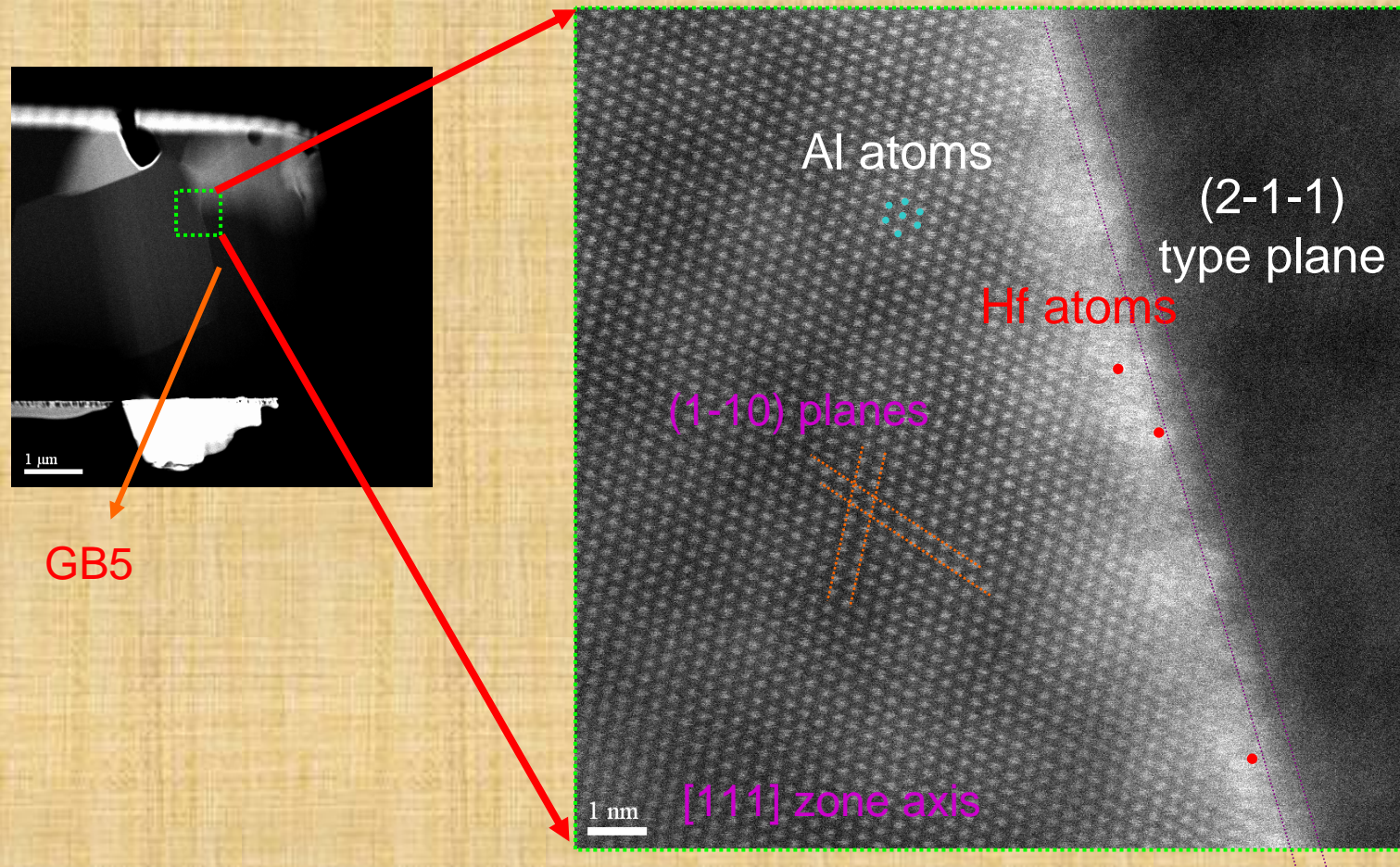
- 500ppm Hf-0.5vol% Ni – Al₂O₃
- 1400°C for 5h
- Inside the Oxidation Region

4 GBs Observed with Surface Steps



- Hf substitutes Al atoms
- Atomic Side Faceting

1 Rough Low Energy Surface GB observed

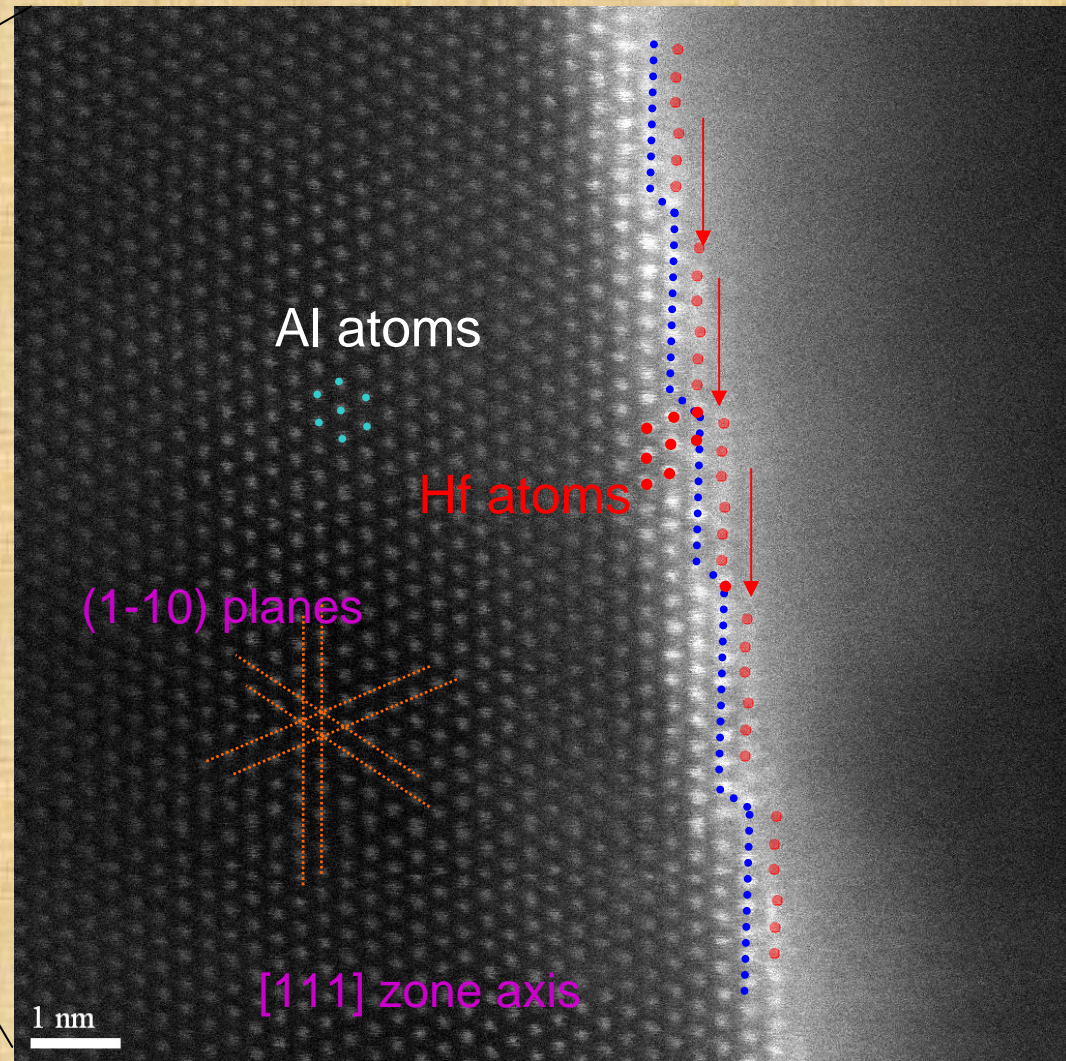
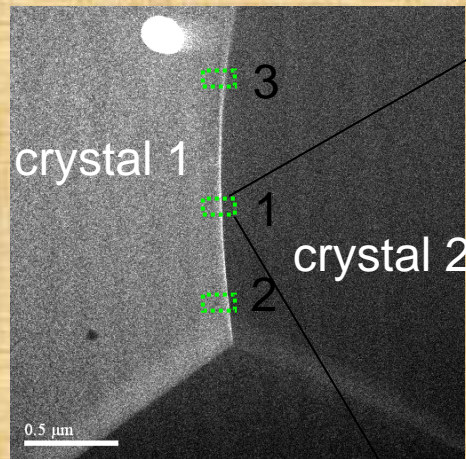


- No steps
- No obvious ordered segregation

Outline

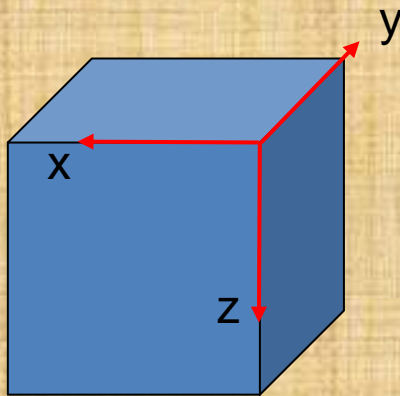
- Introduction
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Ordered Hf segregation



■ one atomic height steps
in the beam direction

Models of steps-model1



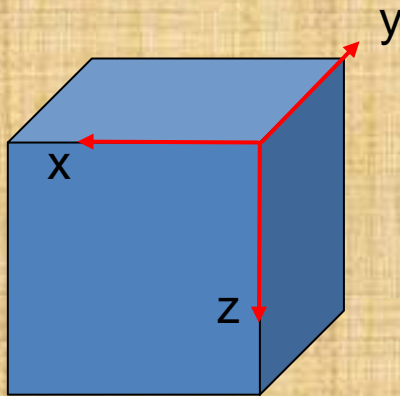
steps in z direction
(z: beam direction)

Model1



one atom scale step; one layer

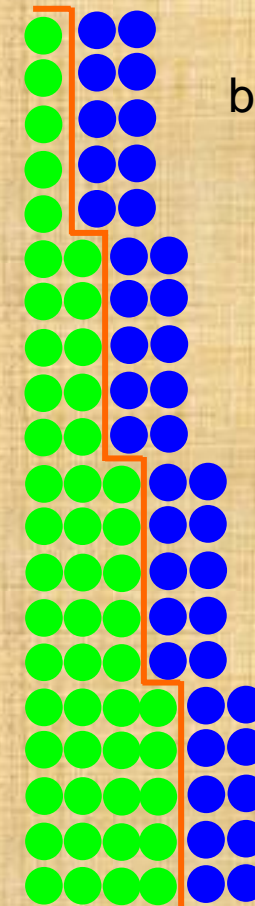
Models of steps—model2



steps in z direction
(z: beam direction)

Model2

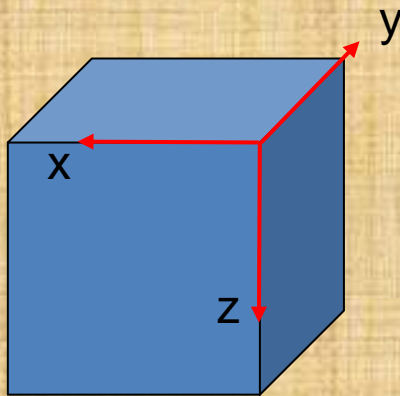
● Hf
● Al



beam direction

one atom scale step; double layer

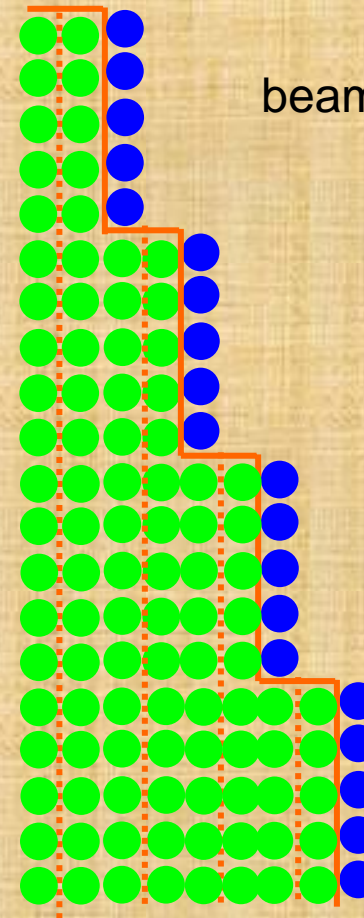
Models of steps—model3



steps in z direction
(z: beam direction)

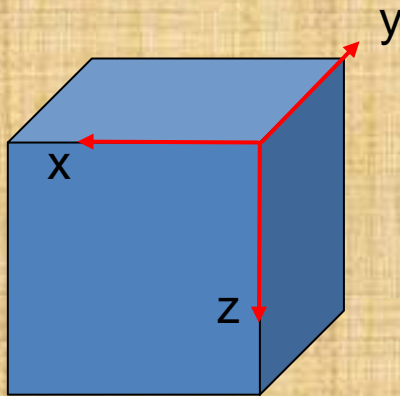
Model3

● Hf
● Al



twp atom scale step; double layer

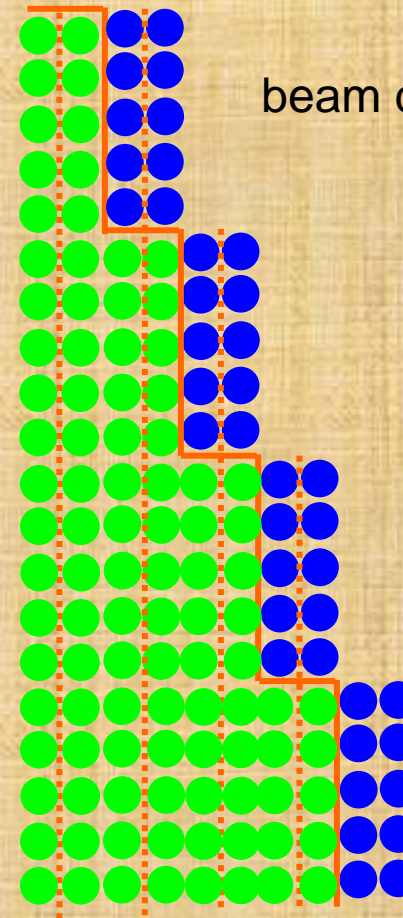
Models of steps—model4



steps in z direction
(z: beam direction)

Model4

● Hf
● Al



beam direction



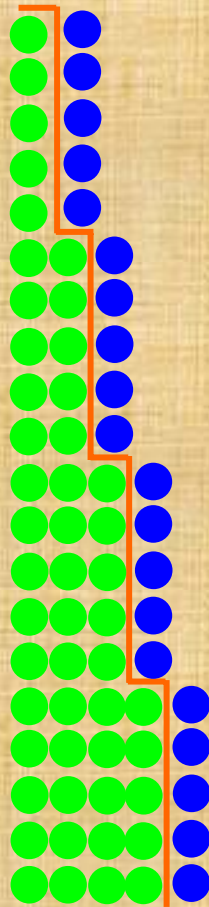
twp atom scale steps; double layer

Model1 Vs Model2



beam direction

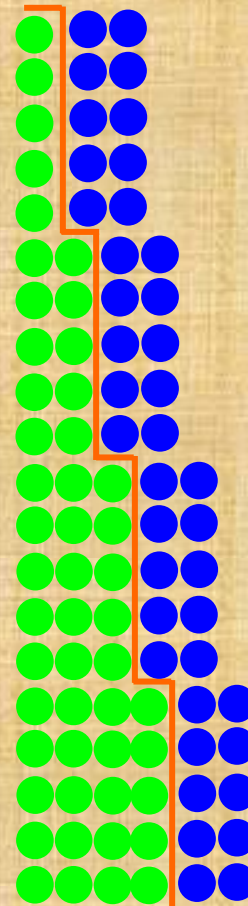
● Hf
● Al



Model1

one atom scale step; one layer segregation

● Hf
● Al

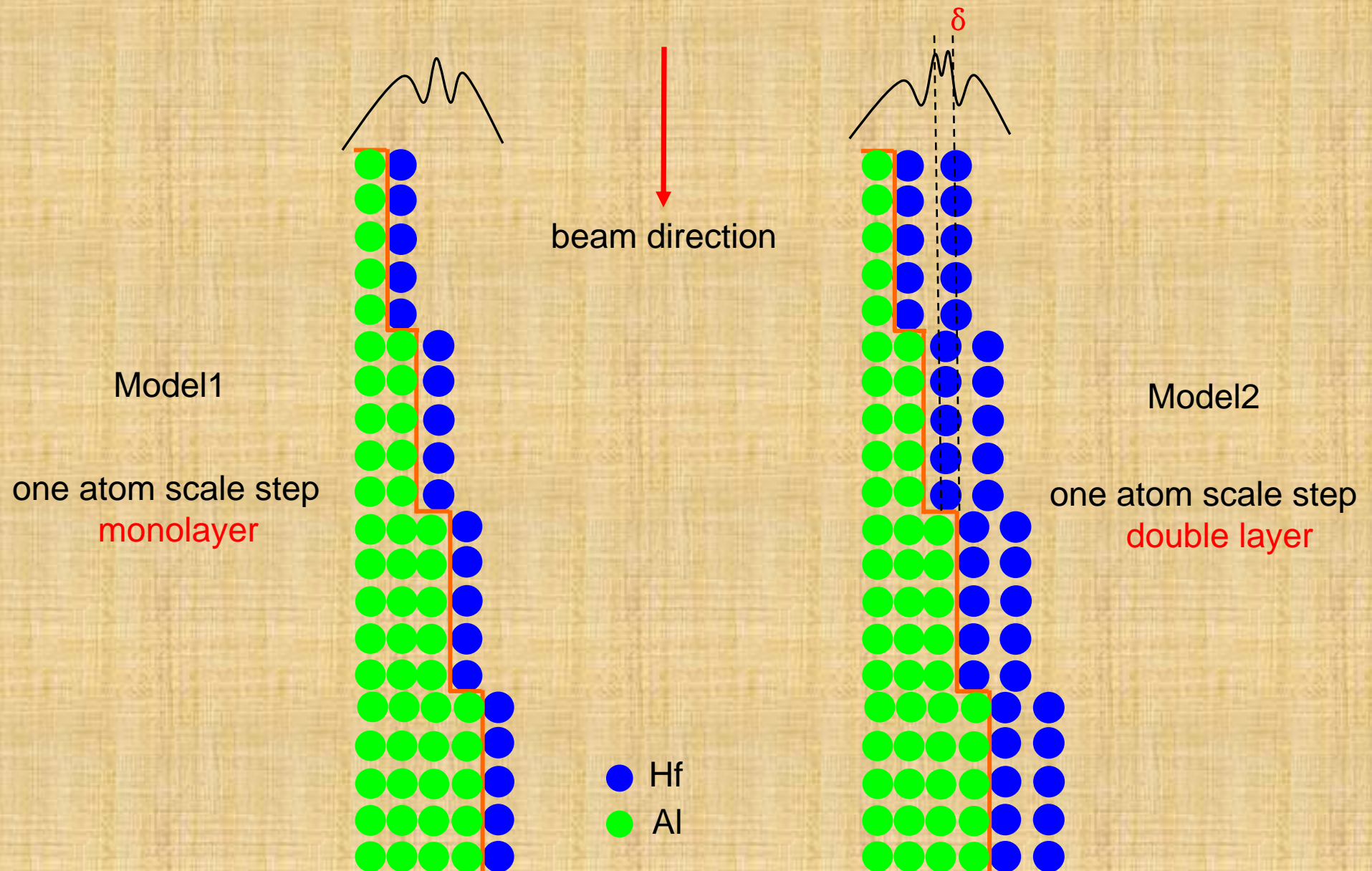


Model2

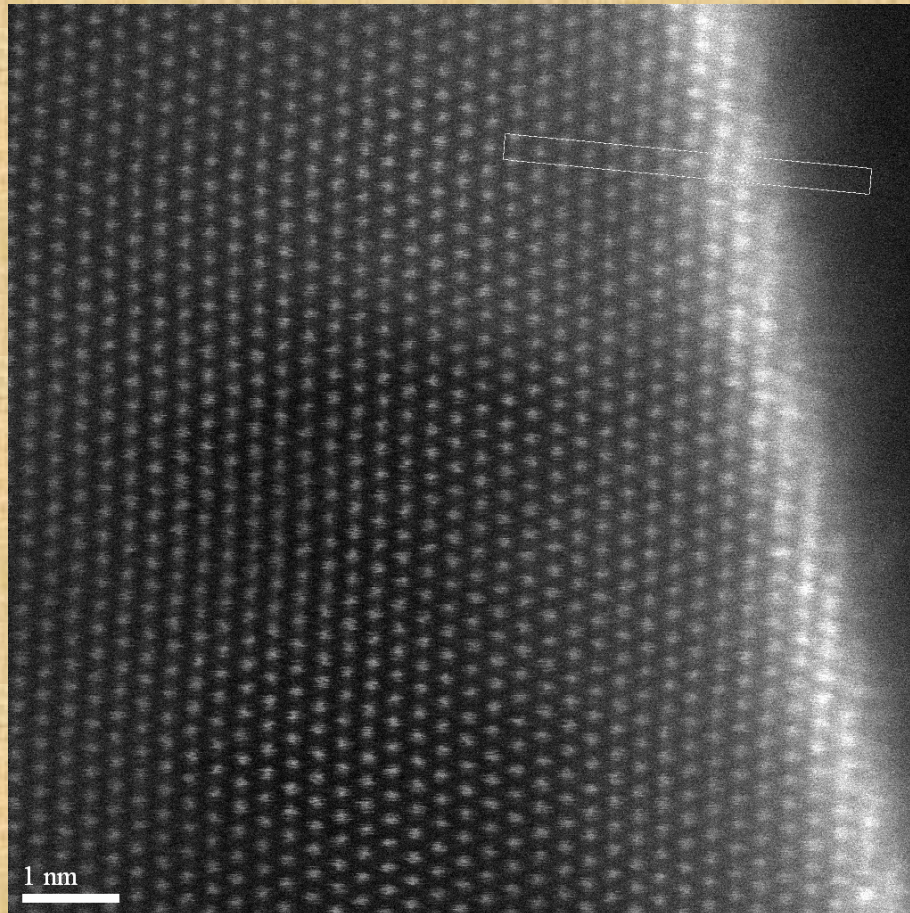
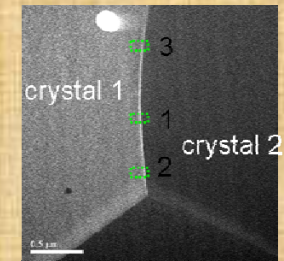
one atom scale step; double layer segregation



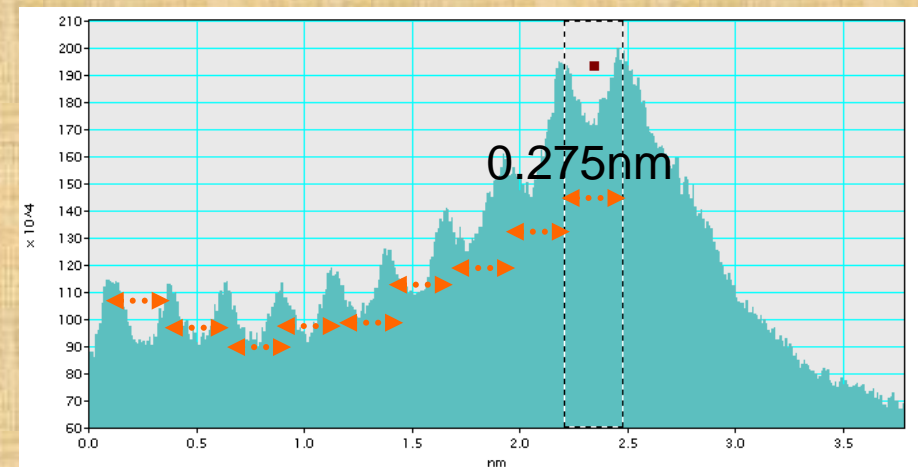
Model1 VS Model2



Model1 VS Model2



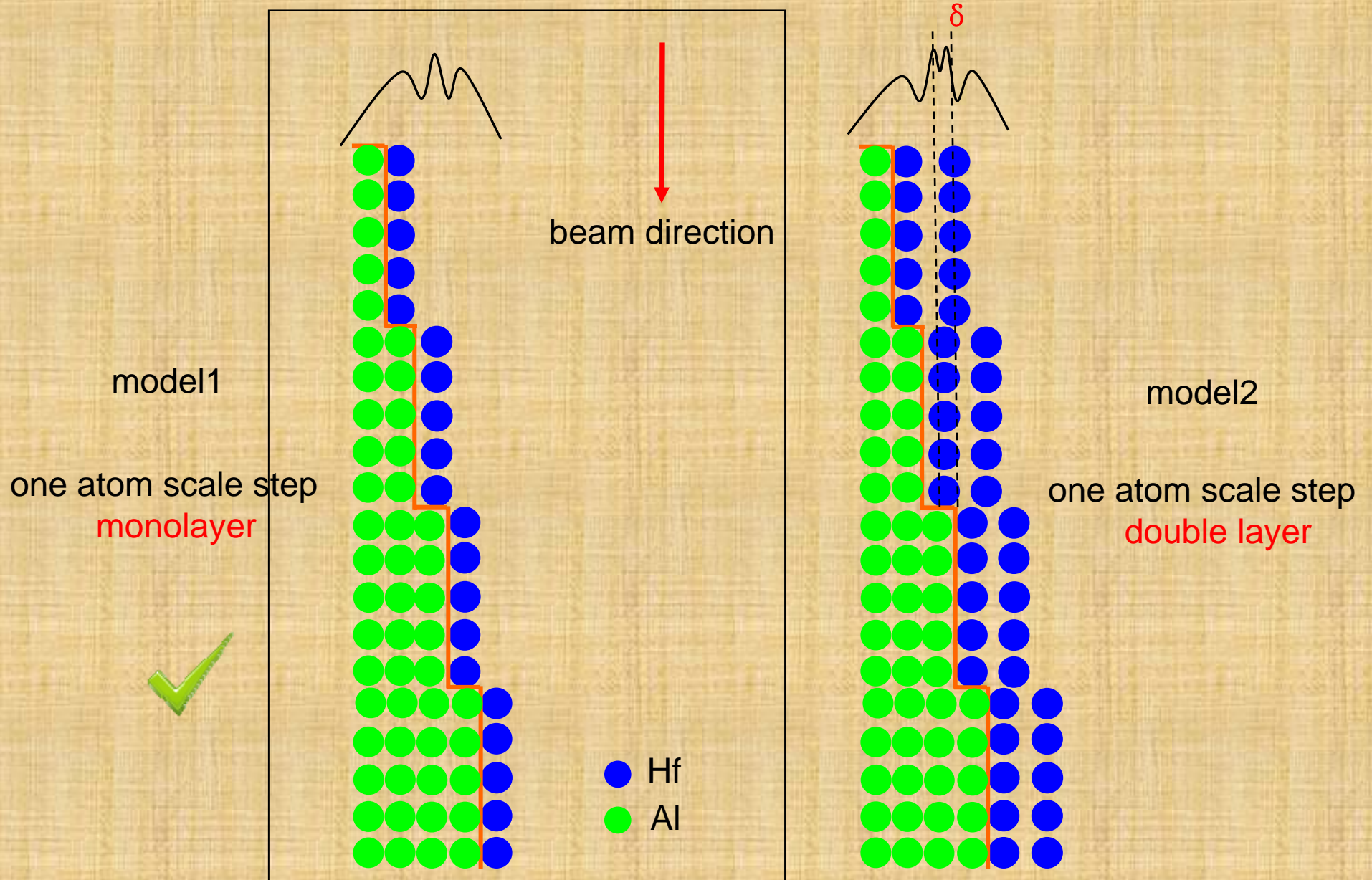
High resolution HAADF image of
Hf doped sample



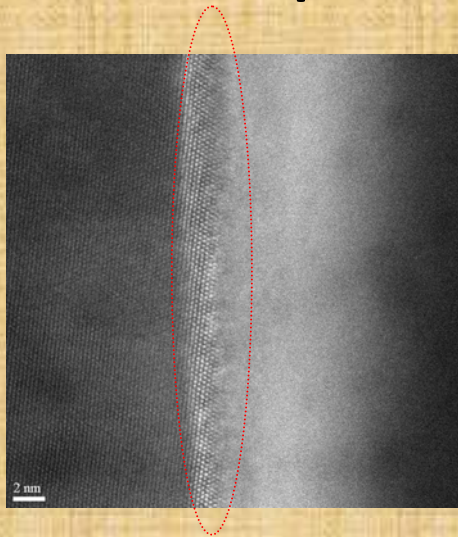
line profile

■ No peak shift or split observed

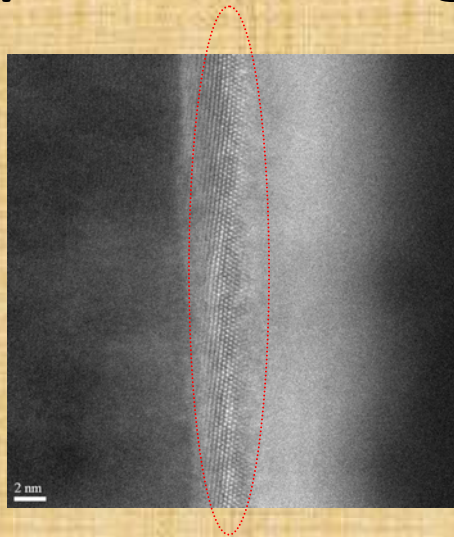
Two Possible Models of Steps



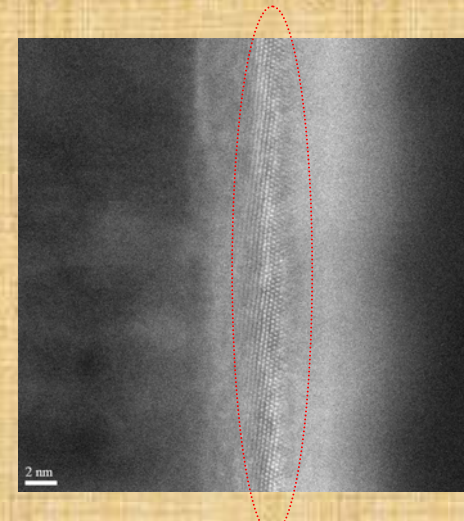
Sharp steps-A through focus study



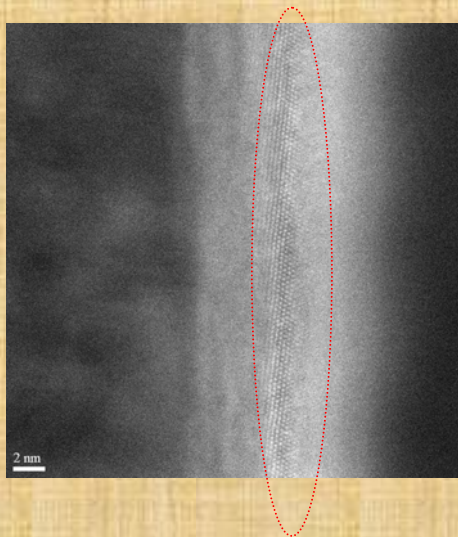
-20nm



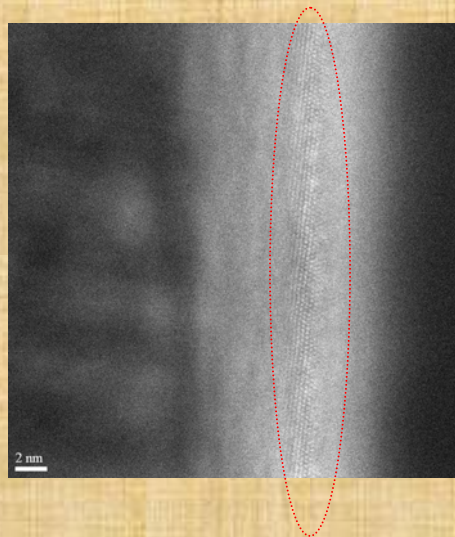
-60nm



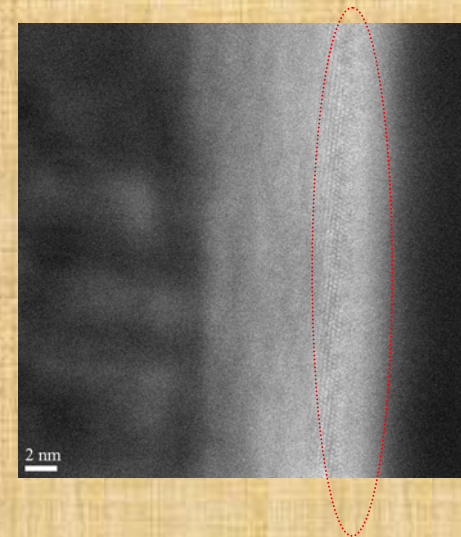
-100nm



-140nm



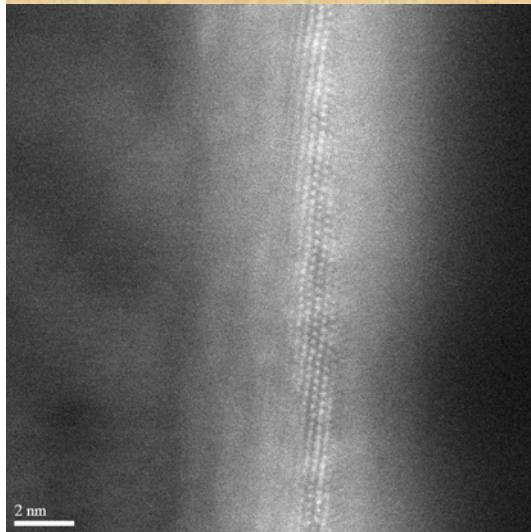
-180nm



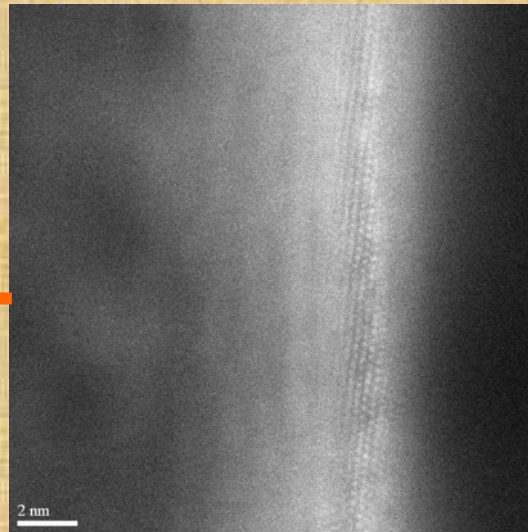
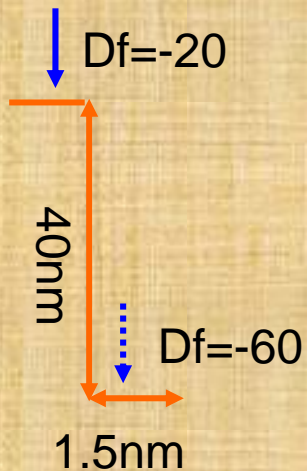
-220nm

Through focus image shows the existence of steps. But, how sharp the steps are ?

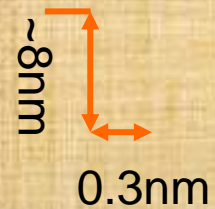
Sharp steps-A through focus study



Df=-20nm

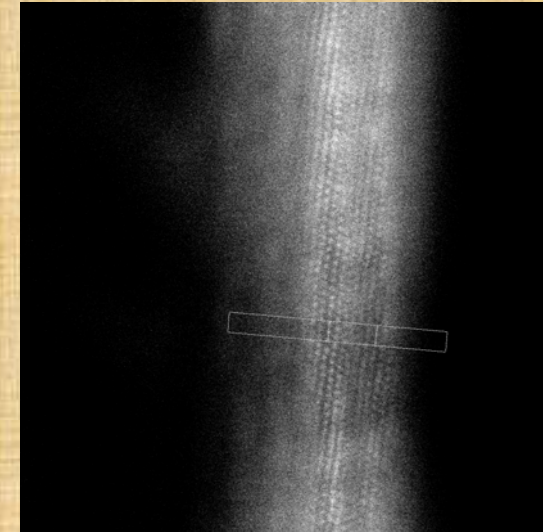


Df=-60nm

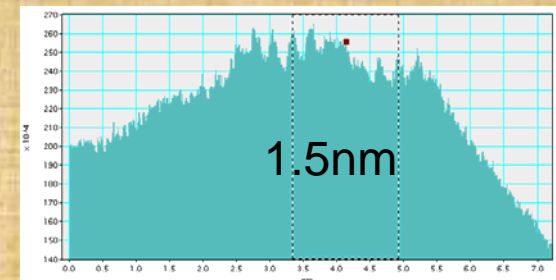


The slope of the steps could be estimated as $40\text{nm}/1.5\text{nm}=26$

=



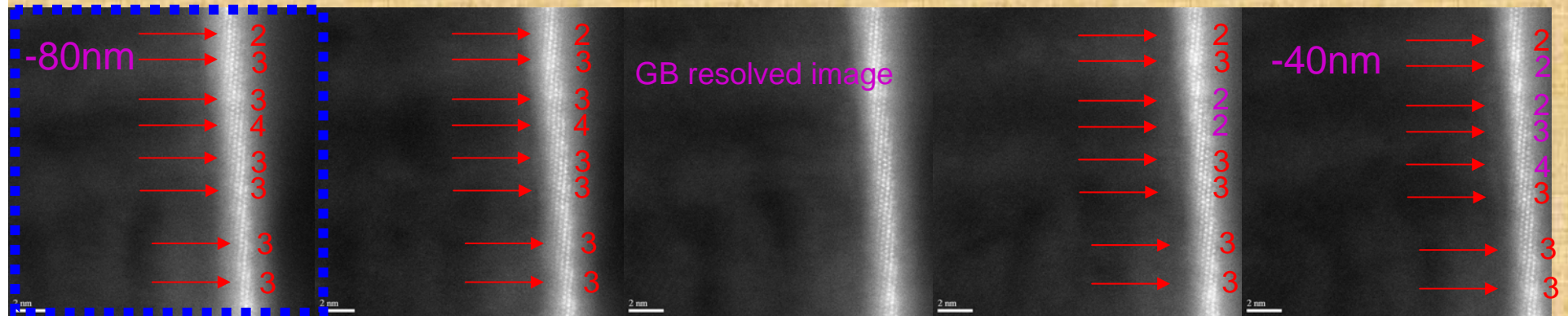
Combined image



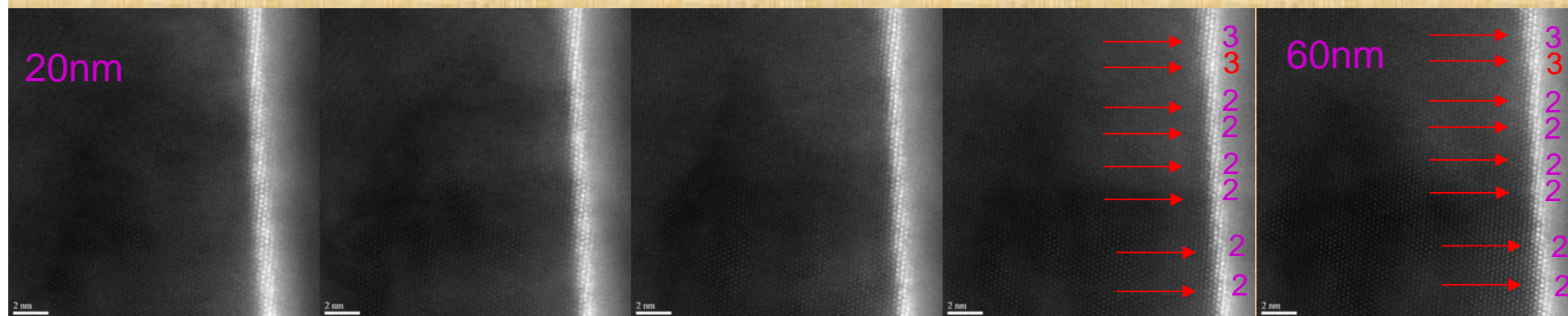
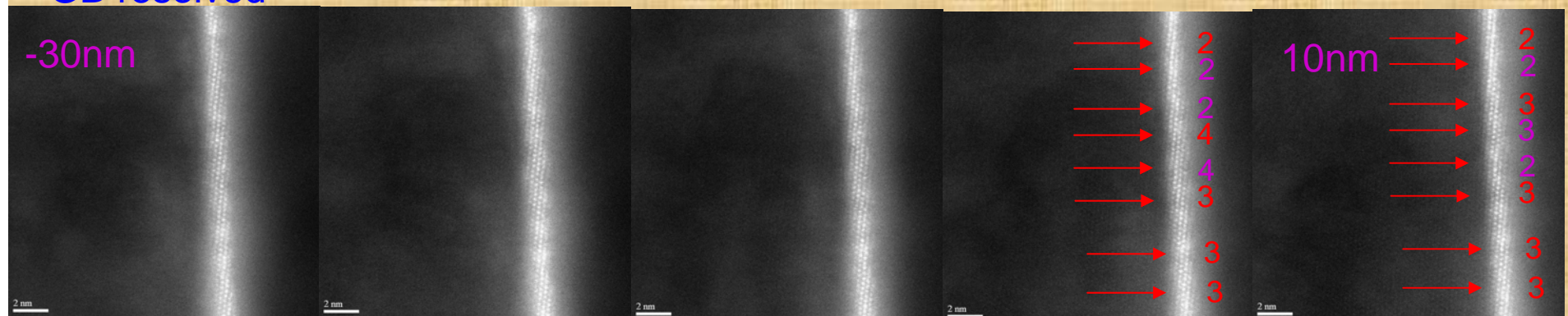
Line profile in the combined image

Sharp steps_ A Through focus study

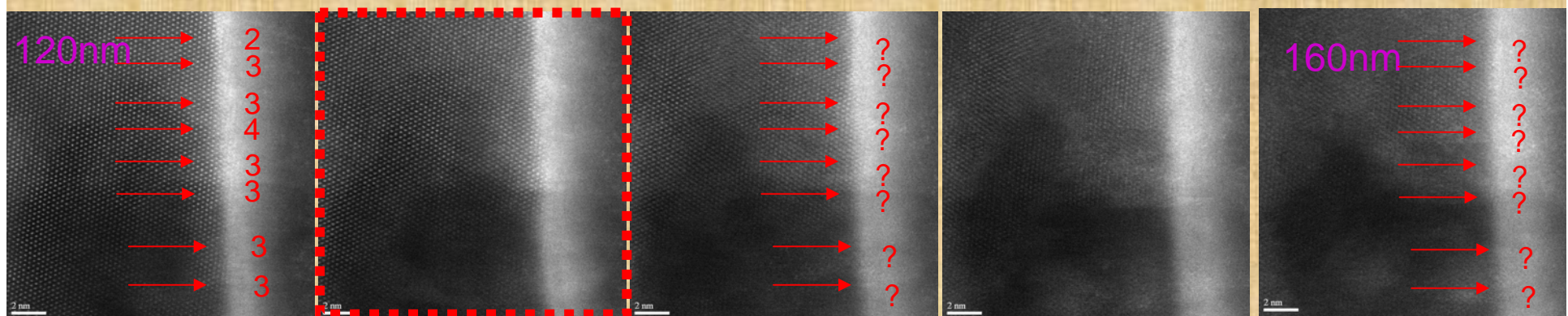
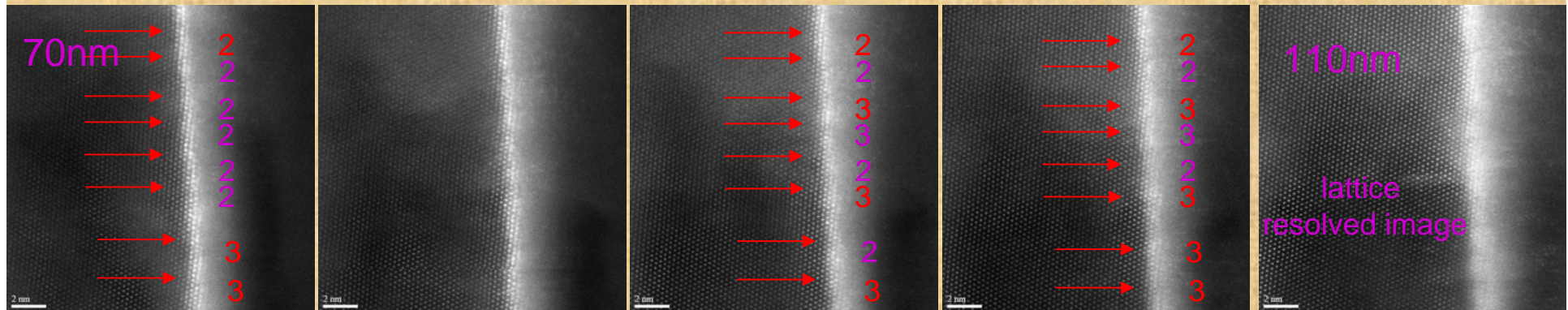
defocus Increment in 10nm



GB resolved



Continued



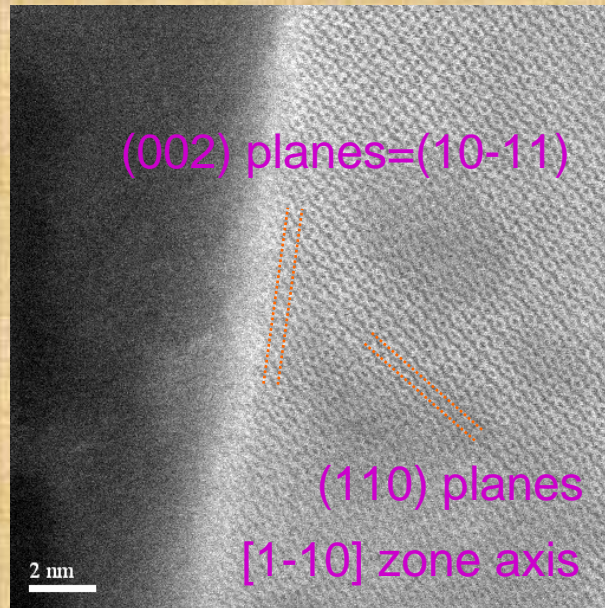
lattice resolved

Through focus imaging suggest that GB and crystal matrix are imaged at different defocus values. Sharp atomic level steps is a reasonable explanation.

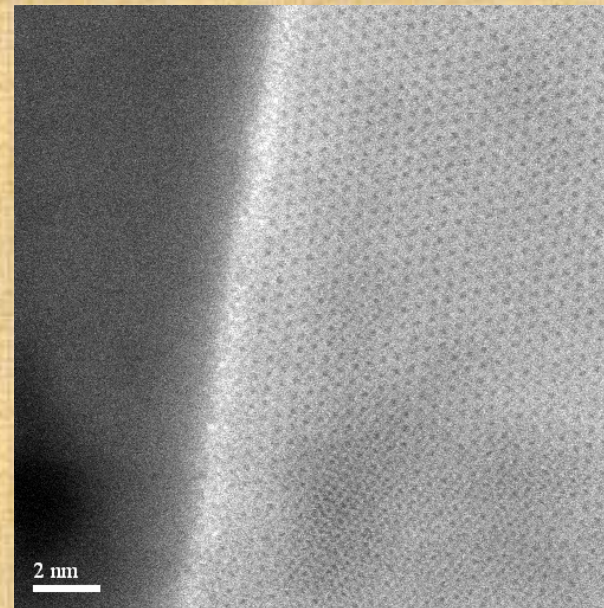
Further STEM image calculation are under way!

Note: Sample is drifting.

Further study-investigation roles of other dopants



DF=-20nm



DF=-60nm

Yttrium doped sample: Primary results

- Yb, Ba, Hf, La segregation behavior
- Crystal morphology change
- Correlation with oxidation property

Conclusions

- Atomic side faceting is generally observed in Hf-doped alumina sample.
- One atomic height steps are found both in the horizontal planes and in the beam directions!
- It should be admitted that, the substitution of Hf atoms into the Al atoms, which is periodic, should have direct correlation with the improved oxidation behavior of Hf-doped alumina.

Acknowledgements

- Animesh Kundu, Patrick Cantwell, Rob Keyse, and Qian He in Lehigh University for electron microscopy assistance
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Thanks for attention!